



National Accreditation Board for
Testing and Calibration Laboratories

CERTIFICATE OF ACCREDITATION

APPLE METROLOGY CENTRE PRIVATE LIMITED

has been assessed and accredited in accordance with the standard

ISO/IEC 17025:2017

**"General Requirements for the Competence of Testing &
Calibration Laboratories"**

for its facilities at

NO. 9/10, PATTUR MAIN ROAD, CHINNAPANICHERY MANGADU, KANCHIPURAM, TAMIL NADU, INDIA

in the field of

CALIBRATION

Certificate Number: CC-4434

Issue Date: 07/06/2025

Valid Until: 06/06/2029

This certificate is re-issued in view of amendment in the scope of accreditation.

This certificate remains valid for the Scope of Accreditation as specified in the annexure subject to continued satisfactory compliance to the above standard & the relevant requirements of NABL.

(To see the scope of accreditation of this laboratory, you may also visit NABL website www.nabl-india.org)

Name of Legal Entity: APPLE METROLOGY CENTRE PRIVATE LIMITED

Signed for and on behalf of NABL



Anita Rani
Director

Dr. Ramanand N. Shukla
Chief Executive Officer



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S.No	Discipline / Group	Measurand or Reference Material/Type of instrument or material to be calibrated or measured / Quantity Measured /Instrument	Calibration or Measurement Method or procedure	Measurement range and additional parameters where applicable(Range and Frequency)	* Calibration and Measurement Capability(CMC)(±)
Permanent Facility					
1	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current (50 Hz to 1 kHz)	Using 6½ DMM by Direct Method	1 A to 3 A	3.5 % to 0.56 %
2	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current (50 Hz to 1 kHz)	Using 6½ DMM by Direct Method	1 mA to 100 mA	0.2 % to 0.31 %
3	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current (50 Hz to 1 kHz)	Using 6½ DMM by Direct Method	100 µA to 1 mA	1.02 % to 0.2 %
4	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current (50 Hz to 1 kHz)	Using 6½ DMM by Direct Method	100 mA to 1 A	0.58 % to 3.5 %



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5	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current (50 Hz to 1 kHz)	Using 6½ DMM by Direct Method	30 µA to 100 µA	1.74 % to 1.02 %
6	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC High Voltage @50 Hz	Using High Voltage Divider with kV Meter by Comparison Method	1 kV to 100 kV	2.38 % to 2.37 %
7	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC High Voltage @50 Hz	Using High Voltage Divider with kV Meter and High Voltage Source by Comparison Method	1 kV to 30 kV	2.0 %
8	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Voltage (50 Hz to 1 kHz)	Using 6½ DMM by Direct Method	1 mV to 100 mV	2.59 % to 0.087 %
9	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Voltage (50 Hz to 1 kHz)	Using 6½ DMM by Direct Method	100 mV to 750 V	0.087 % to 0.12 %



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10	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Active Power (1Ph, 2W) @ (50 Hz) (30 V to 480 V , 0.05 A to 20 A,(0.1 Lead/Lag to UPF)	Using MPC by Direct Method	0.15 W to 9.6 kW	3.8 % to 0.19 %
11	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current (>1 kHz to 5 kHz)	Using MPC by Direct Method	1 A to 10 A	0.085 % to 0.15 %
12	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current (>1 kHz to 5 kHz)	Using MPC by Direct Method	10 µA to 100 µA	2.65 % to 0.11 %
13	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current (>1 kHz to 5 kHz)	Using MPC by Direct Method	10 A to 30 A	0.15 % to 0.5 %
14	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current (>1 kHz to 5 kHz)	Using MPC by Direct Method	100 µA to 1 A	0.11 % to 0.085 %
15	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current (45 Hz to 1 kHz)	Using MPC by Direct Method	1 A to 3 A	0.06 % to 0.098 %



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16	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current (45 Hz to 1 kHz)	Using MPC by Direct Method	10 µA to 100 µA	2.6 % to 0.11 %
17	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current (45 Hz to 1 kHz)	Using MPC by Direct Method	100 µA to 1 A	0.11 % to 0.06 %
18	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current (45 Hz to 1 kHz)	Using MPC by Direct Method	3 A to 30 A	0.098 % to 0.101 %
19	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current (50 Hz)	Using MPC and Current Coil by Direct Method	30 A to 1000 A	0.49 % to 0.37 %
20	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage (>1 kHz to 10 kHz)	Using MPC by Direct Method	300 V to 1000 V	0.021 % to 0.034 %
21	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage (>1 kHz to 20 kHz)	Using MPC by Direct Method	1 mV to 10 mV	0.84 % to 0.095 %



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22	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage (>1 kHz to 20 kHz)	Using MPC by Direct Method	10 mV to 300 V	0.095 % to 0.022 %
23	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage (10 Hz to 1 kHz)	Using MPC by Direct Method	1 mV to 10 mV	0.84 % to 0.095 %
24	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage (10 Hz to 1 kHz)	Using MPC by Direct Method	10 mV to 300 V	0.095 % to 0.022 %
25	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage (40 Hz to 1 kHz)	Using MPC by Direct Method	300 V to 1000 V	0.021 % to 0.034 %
26	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 1 kHz	Using Decade Capacitance box By Direct Method	10 pF to 100 µF	1.45 % to 1.46 %
27	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Inductance @ 1 kHz	Using Decade Inductance box By Direct Method	1 mH to 10 H	1.54 % to 1.45 %



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28	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Phase Angle	Using MPC by Direct Method	0 ° to 180 °	0.12 °
29	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Power Factor	Using MPC by Direct Method	0.1 PF (Lead/Lag) to UPF to	0.001 PF
30	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Current	Using 6½ DMM by Direct Method	1 µA to 1 mA	0.27 % to 0.062 %
31	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Current	Using 6½ DMM by Direct Method	1 A to 3 A	0.06 % to 0.14 %
32	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Current	Using 6½ DMM by Direct Method	1 mA to 100 mA	0.061 % to 0.031 %
33	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Current	Using Shunt and DMM by VI Method	100 A to 1200 A	0.5 %



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34	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Current	Using 6½ DMM by Direct Method	100 mA to 1 A	0.031 % to 0.06 %
35	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Current	Using Shunt and DMM by VI Method	30 A to 100 A	0.5 %
36	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC High Voltage	Using High Voltage Divider with kV Meter by Comparison Method	1 kV to 100 kV	2.05 % to 1.98 %
37	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC High Voltage	Using High Voltage Divider with kV Meter and High Voltage Source by Comparison Method	1 kV to 40 kV	2.0 %
38	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Voltage	Using 6½ DMM by Direct Method	1 mV to 100 mV	0.42 % to 0.008 %
39	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Voltage	Using 6½ DMM by Direct Method	100 mV to 1000 V	0.008 % to 0.0057 %



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40	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	Resistance (4W)	Using 6½ DMM by Direct Method	0.1 ohm to 10 kohm	0.42 % to 0.059 %
41	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	Resistance (4W)	Using 6½ DMM by Direct Method	10 kohm to 100 kohm	0.059 % to 0.016 %
42	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	Resistance 2W	Using 6½ DMM by Direct Method	100 kohm to 100 Mohm	0.016 % to 1.32 %
43	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MPC by Direct Method	1 µA to 100 µA	1.01 % to 0.021 %
44	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MPC by Direct Method	1 A to 10 A	0.018 % to 0.048 %
45	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MPC by Direct Method	10 A to 30 A	0.048 % to 0.10 %



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46	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MPC by Direct Method	100 µA to 100 mA	0.021 % to 0.011 %
47	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MPC by Direct Method	100 mA to 1 A	0.011 % to 0.018 %
48	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MPC and Current Coil by Direct Method	30 A to 1000 A	0.42 % to 0.34 %
49	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Power (10 mV to 1000 V, 10 mA to 30 A)	Using MPC by Direct Method	100 mW to 30 kW	3.8 % to 0.37 %
50	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Voltage	Using MPC by Direct Method	1 mV to 100 mV	0.12 % to 0.003 %
51	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Voltage	Using MPC by Direct Method	10 V to 1000 V	0.0011 % to 0.002 %



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52	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Voltage	Using MPC by Direct Method	100 mV to 10 V	0.003 % to 0.0011 %
53	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance (2-Wire) @ 1 kV to 5 kV	Using Decade Resistance Box By Direct Method	10 Mohm to 1 Tohm	2.1 % to 3.8 %
54	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance (2/4-Wire)	Using Decade Resistance Box By Direct Method	1 ohm to 10 ohm	0.06 % to 0.03 %
55	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance (2/4-Wire)	Using Decade Resistance Box By Direct Method	10 mohm to 1 ohm	1.16 % to 0.007 %
56	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance (2/4-Wire)	Using Decade Resistance Box By Direct Method	10 Mohm to 100 Mohm	0.61 %
57	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance (2/4-Wire)	Using Decade Resistance Box By Direct Method	10 ohm to 10 Mohm	0.03 % to 0.61 %



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58	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance (2/4-Wire)	Using Decade Resistance Box By Direct Method	100 Mohm to 10 Gohm	0.61 % to 0.83 %
59	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance(2W)	Using MPC by Direct Method	10 Mohm to 100 Mohm	0.0054 % to 0.049 %
60	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance(2W)	Using MPC by Direct Method	100 kohm to 10 Mohm	0.0029 % to 0.0054 %
61	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance(2W)	Using MPC by Direct Method	100 Mohm to 1000 Mohm	0.049 % to 0.6 %
62	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance(4W/2W)	Using MPC by Direct Method	1 ohm to 10 ohm	0.12 % to 0.015 %
63	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance(4W/2W)	Using MPC by Direct Method	10 ohm to 100 kohm	0.015 % to 0.0029 %



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64	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope (AC Amplitude @1 kHz to 10 kHz)	Using MPC by Direct Method	1 mV to 120 V	0.99 % to 0.1 %
65	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope (Bandwidth)	Using Signal Generators by Direct Method	1 GHz to 4 GHz	0.46 dB to 0.5 dB
66	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope (Bandwidth)	Using MPC by Direct Method	50 kHz to 600 MHz	1.62 % to 3.37 %
67	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope (Bandwidth)	Using MPC by Direct Method	600 MHz to 1 GHz	3.37 % to 5.7 %
68	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope (DC Amplitude)	Using MPC by Direct Method	5 mV to 120 V	0.99 % to 0.059 %
69	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope (Time Marker)	Using Signal Generators by Direct Method	0.5 ns to 20 ns	0.004 % to 0.00098 %



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70	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope (Time Marker)	Using MPC by Direct Method	20 ns to 2 s	0.029 % to 0.00042 %
71	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Antenna Factor (9 kHz to 30 MHz)	Using VectorNetwork Analyzer, RF Reference Sourceand Signal Analyzeras per ANSI C63.5	- 5 dB to 96 dB	0.69 dB
72	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Automotive Transient Pulses 1,2a,2b,3a,3b,4,5 : Pulse Width/Duration	Using Digital Oscilloscope, Differential Probe, passive voltage probe and load resistors by Direct Method as per ISO 7637-2, SAE J-1113-11	50 ns to 10 s	0.23 %
73	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Automotive Transient Pulses 1,2a,2b,3a,3b,4,5 : Rise Time/Fall Time	Using Digital Oscilloscope, Differential Probe, passive voltage probe and load resistors by Direct Method as per ISO 7637-2, SAE J-1113-11	1 ns to 100 ms	2.32 %



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74	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Automotive Transient Pulses 1,2a,2b,3a,3b,4,5 : Amplitude	Using Digital Oscilloscope & Differential Probe by Direct Method as per ISO 7637-2, SAE J-1113-11	-600 V to 400 V	2.92 %
75	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Capacitive coupling clamp - Pulse Duration	Using Digital Oscilloscope & Load Resistor as per ISO 7637-3 by Direct Method	150 ns	0.08 %
76	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Capacitive coupling clamp - Rise Time	Using Digital Oscilloscope & Load Resistor as per ISO 7637-3 by Direct Method	5 ns	1.63 %
77	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Capacitive coupling clamp - Voltage Amplitude	Using Digital Oscilloscope & Load Resistor as per ISO 7637-3 by Direct Method	-400 V to 400 V	3 %
78	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Combination wave surge test system (Generator, CDN output) a)Voltage Amplitude	Using Digital Storage Oscilloscope, High Voltage Differential Probe as per IEC 61000-4-5 by Direct Method	±0.25 kV to ±7.0 kV	3.84 %



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79	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Combination wave surge test system (Generator, CDN output) b)Voltage front time	Using Digital Storage Oscilloscope, High Voltage Differential Probe as per IEC 61000-4-5 by Direct Method	1.2 μ s	0.09 μ s
80	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Combination wave surge test system (Generator, CDN output) c)Voltage Duration	Using Digital Storage Oscilloscope, High Voltage Differential Probe as per IEC 61000-4-5 by Direct Method	50 μ s	0.03 μ s
81	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Combination wave surge test system (Generator, CDN output) d)current amplitude	Using Digital Storage Oscilloscope, Current probe as per IEC 61000-4-5 by Direct Method	$\pm$ 20.83 A to $\pm$ 3.5 kA	1.96 %
82	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Combination wave surge test system (Generator, CDN output) e)current front time	Using Digital Storage Oscilloscope, Current probe as per IEC 61000-4-5 by Direct Method	2.5 μ s to 8 μ s	1.64 %



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83	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Combination wave surge test system (Generator, CDN output) f) current Duration	Using Digital Storage Oscilloscope, Current probe as per IEC 61000-4-5 by Direct Method	20 μ s to 25 μ s	0.08 %
84	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Coupling Factor/Coupling loss /Decoupling of common mode Disturbance /Insertion loss /RF Attenuation/Isolation /Voltage Division Factor (EM Clamp,SWR Bridge,Directional Coupler) 9 kHz to 4.5 GHz	Using Vector network analyzer by direct method	0 dB to 80 dB	0.69 dB
85	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	CouplingFactor/loss/ CommonModelmped ance/Directivity/Inse rtion loss/RFAttenuation/Is olation/VDF (20 Hz to 9 kHz)	Using Signal Generator, Function Generator Spectrum Analyzer by Direct Method	1 dB to 60 dB	0.23 dB to 1.78 dB



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86	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	CouplingFactor/loss/CommonModelmpedance/Directivity/Insertion loss/RFAttenuation/Isolation/VDF (9 kHz to 20 GHz)	Using Vector network analyzer by Direct method	0.1 dB to 90 dB	0.74 dB
87	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Damped oscillatory magnetic field strength generator with Standard Coil - oscillation Period @ 100 kHz	Using Digital Storage Oscilloscope, Current probe by Direct Method as per IEC 61000-4-10:2016	10 μ s	2.5 %
88	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Damped oscillatory magnetic field strength generator with Standard Coil - Peak current & decaying (Pk5) & (Pk10)	Using Digital Storage Oscilloscope, Current probe by Direct Method as per IEC 61000-4-10:2016	5 A to 100 A	3.91 % to 2.03 %
89	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Damped oscillatory magnetic field strength generator with Standard Coil - Repetition time @1 MHz	Using Digital Storage Oscilloscope, Current probe by Direct Method as per IEC 61000-4-10:2016	2.5 ms	3.3 %



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90	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Damped oscillatory magnetic field strength generator with Standard Coil - Oscillation Period @ 1 MHz	Using Digital Storage Oscilloscope, Current probe by Direct Method as per IEC 61000-4-10:2016	1 μ s	5.05 %
91	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Damped oscillatory magnetic field strength generator with Standard Coil: Repetition time @ 100 kHz	Using Digital Storage Oscilloscope, Current probe by Direct Method as per IEC 61000-4-10:2016	25 ms	3.3 %
92	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Damped Oscillatory wave Generator (Voltage Amplitude) (Voltage Decay) Decay in Peak 10 to be 50% of peak 1 value	Using Voltage Differential Probe & Digital Oscilloscope as per IEC 61000-4-18 by Direct Method	± 0.25 kV to ± 4.0 kV	2.81 % to 3.9 %
93	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Damped Oscillatory wave Generator - Slow and Fast(Repetition Rate)	Using Voltage Differential Probe & Digital Oscilloscope as per IEC 61000-4-18 by Direct Method	40 Hz, 400 Hz, 5 kHz	0.06 % to 0.13 %



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94	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Damped Oscillatory wave Generator-Slow and Fast (Current Amplitude)	Using Current Probe & Digital Oscilloscope as per IEC 61000-4-18 by Direct Method	±1.25 A to ±12.5 A	1.88 % to 1.95 %
95	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Damped Oscillatory wave Generator-Slow and Fast (Oscillation Frequency)	Using Voltage Differential Probe & Digital Oscilloscope as per IEC 61000-4-18 by Direct Method	100 kHz, 1 MHz, 3 MHz, 10 MHz and 30 MHz	1.21 % to 0.38 %
96	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Damped Oscillatory wave Generator-Slow and Fast (Rise Time)	Using Voltage Differential Probe & Digital Oscilloscope as per IEC 61000-4-18 by Direct Method	5 ns to 75 ns	3.31 % to 0.23 %
97	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrical fast transient test system (Generator output) Burst Period	Using Digital Storage Oscilloscope with Load Resistor 50 ohm & 1000 ohm as per IEC 61000-4-4 by Direct Method	300 ms	0.19 ms
98	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrical fast transient test system (Generator output) e) Burst Duration (2.5 kHz/5 kHz/100 kHz/1000 kHz)	Using Digital Storage Oscilloscope with Load Resistor 50 ohm & 1000 ohm as per IEC 61000-4-4 by Direct Method	0.75 ms to 15 ms	0.05 ms



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99	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrical fast transient test system (Generator output, Capacitive Clamp) d)Repetition frequency (inverse)	Using Digital Storage Oscilloscope with Load Resistor 50 ohm & 1000 ohm as per IEC 61000-4-4 by Direct Method	2.5,5,100,1000 kHz	0.15 %
100	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrical fast transient test system (Generator, CDN output, Capacitive Clamp) a) Pulse Amplitude	Using Digital Storage Oscilloscope with Load Resistor 50 ohm & 1000 ohm as per IEC 61000-4-4 by Direct Method	±125 V to ±5.5 kV	3 %
101	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrical fast transient test system (Generator, CDN output, Capacitive Clamp) Pulse Rise time	Using Digital Storage Oscilloscope with Load Resistor 50 ohm & 1000 ohm as per IEC 61000-4-4 by Direct Method	5 ns to 5.5 ns	0.17 ns
102	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrical fast transient test system (Generator, CDN output, Capacitive Clamp) Pulse width	Using Digital Storage Oscilloscope with Load Resistor 50 ohm & 1000 ohm as per IEC 61000-4-4 by Direct Method	45 ns to 50 ns	0.17 ns
103	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrostatic Discharge Generator a)First peak current (± 2.0 kV TO ±30 kV)	Using Digital Storage Oscilloscope , ESD Target as per IEC 61000-4-2, SAE J1113-13, ISO 10605	±6.38 A to ±146.25 A	6.64 %



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104	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrostatic Discharge Generator b)Rise time	Using Digital Storage Oscilloscope , ESD Target as per IEC 61000-4-2, SAE J1113-13, ISO 10605	0.6 ns to 1 ns	11.44 %
105	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrostatic Discharge Generator c) Current @ 30 ns/65ns/180ns/400ns (± 2.0 kV TO ±30 kV)	Using Digital Storage Oscilloscope , ESD Target as per IEC 61000-4-2, SAE J1113-13, ISO 10605	±0.385 A to ±78 A	6.27 %
106	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrostatic Discharge Generator d) Current @ 60 ns/130ns/360ns/800ns (± 2.0 kV TO ±30 kV)	Using Digital Storage Oscilloscope , ESD Target as per IEC 61000-4-2, SAE J1113-13, ISO 10605	±0.15 A to ±39 A	6.23 %
107	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrostatic Discharge Generator-Generator DC output voltage	Using High voltage probe, Dual display Multimeter as per IEC 61000- 4-2 , SAE J1113-13 ISO 10605	±1 kV to ±30 kV	3.95 %
108	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	ElectrostaticDischarge Generator)Second peak current(± 2.0 kV TO ±30 kV)	Using Digital Storage Oscilloscope ESD Target as per Direct Method as per IEC 61000-4- 2:2025	±2.7 A to ±94.5 A	6.64 %



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109	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Impedance 9 kHz to 400 MHz	Using Vector network analyzer by direct method	1 ohm to 300 ohm	4 %
110	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Impulse / Surge(Peak Voltage)	Using HV Probe with Oscilloscope By Direct Method	±0.1 kV to ±20 kV	3.8 % to 4.1 %
111	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Impulse magneticField Generator with Standard Coil - Front time	Using DigitalStorage Oscilloscope,Current probe byDirect Method as perIEC 61000-4- 9:2016	8 µs	6.05 %
112	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Impulse magneticField Generator with Standard Coil - Peak current	Using DigitalStorage Oscilloscope,Current probe byDirect Method as perIEC 61000-4- 9:2016	86 A/m to 2200 A/m	6.05 %
113	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Impulse magneticField Generator withStandard Coil - Duration	Using DigitalStorage Oscilloscope,Current probe byDirect Method as perIEC 61000-4- 9:2016	20 µs	5.25 %
114	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Longitudinal conversion loss (Impedance stabilization Network) 9 kHz to 30 MHz	Using Vector network analyzer by direct method AS Per CISPR 22,CISPR 32	0 dB to 60 dB	0.69 dB



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115	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Low frequency Transfer impedance/ Resistance Target	Using MPC and 6½ DMM by IEC 61000 4-2 & ISO 10605	2 ohm	2.8 %
116	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Phase Angle (9 kHz to 400 MHz)	Using Vector network analyzer by direct method CISPR 16-1-2	-90 ° to 90 °	1.1 °
117	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Phase Shifting (Surge/ Ringwave/ Dips Generator)	Using Voltage Differential Probe & Digital Oscilloscope as per IEC 61000-4-5, IEC 61000-4-12, IEC 61000-4-11 by Direct Method	0 ° to 360 °	0.08 ° to 0.23 °
118	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Power Frequency Magnetic Field Generator with Standard Coil - Magnetic field strength @50 Hz	Using Flexible Current probe with Clamp meter by Direct Method As per IEC 61000-4-8:2009	100 A to 1000 A	3.59 % to 3.5 %
119	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Return loss/ VSWR/Reflection coefficient (Transient limiter, Directional coupler, Attenuator, Cable, Pre amplifier, Terminator) 9 kHz to 4.5 GHz	Using Vector network analyzer by Direct Method	1 dB to 46 dB	0.69 dB



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120	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Return loss/VSWR/Reflection Co-efficient (9 kHz to 20 GHz)	Using Vector network analyzer by Direct method	0.1 dB to (-) 60 dB	0.74 dB
121	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Ring Wave Generator a. Voltage Amplitude (Voltage Decay) Pk2 40% to 110% of Pk1, Pk3 40 to 80% of Pk2, Pk4 40% to 80% of Pk3	Using Digital Storage Oscilloscope , High voltage Differential probe as per IEC 61000-4-12 by Direct Method	±0.25 kV to ±7.0 kV	4 %
122	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Ring Wave Generator - current amplitude	Using Digital Storage Oscilloscope , Current probe as per IEC 61000-4-12 by Direct Method	±8.33 A to ±583.33 A	1.96 %
123	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Ring Wave Generator - Voltage Rise time	Using Digital Storage Oscilloscope , High voltage Differential probe as per IEC 61000-4-12 by Direct Method	0.5 µs	0.008 µs
124	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Ring Wave Generator -Current rise time	Using Digital Storage Oscilloscope , Current probe as per IEC 61000-4-12 by Direct Method	1 µs	0.008 µs



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125	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Ring Wave Generator c)Oscillation frequency(period)	Using Digital Storage Oscilloscope , High voltage Differential probe as per IEC 61000-4-12 by Direct Method	100 kHz (10µs)	1.20 %
126	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Telecom surge Generator - Current Amplitude	Using Current Probe & Digital Oscilloscope as per IEC 61000-4-5 by Direct Method	±6.25 A to ±466.66 A	1.90 %
127	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Telecom surge test system - current front time	Using Digital Storage Oscilloscope, Current probe as per IEC 61000-4-5 by Direct Method	5 µs	0.02 µs
128	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Telecom surge test system - current pulse width	Using Digital Storage Oscilloscope, Current probe as per IEC 61000-4-5 by Direct Method	320 µs	0.2 µs
129	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Telecom surge test system - Voltage Amplitude	Using Digital Storage Oscilloscope , High voltage Differential probe as per IEC 61000-4-5 by Direct Method	±0.25 kV to ±7.0 kV	5.68 %



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130	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Telecom surge test system - Voltage front time	Using Digital Storage Oscilloscope , High voltage Differential probe as per IEC 61000-4-5 by Direct Method	10 μ s	0.015 μ s
131	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Telecom surge test system Voltage pulse width	Using Digital Storage Oscilloscope , High voltage Differential probe as per IEC 61000-4-5 by Direct Method	700 μ s	0.42 μ s
132	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Voltage Dips & Interruption Generator Dips/Interruption time	Using Digital Storage Oscilloscope, High voltage Differential probe as per IEC 61000-4-11 & IEC 61000-4-29 by Direct Method	10 ms to 5 s	0.83 %
133	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Voltage Dips & Interruption Generator Output voltage at no load	Using Digital Storage Oscilloscope, High voltage Differential probe as per IEC 61000-4-11 & IEC 61000-4-29 by Direct Method	0 % to 100 %	1.33 %



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134	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Voltage Dips & Interruption Generator Rise/Fall Time(with Load)	Using Voltage Differential Probe & Digital Oscilloscope as per IEC 61000-4-11 & IEC 61000-4-29 by Direct Method	1 μ s to 50 μ s	6.5 %
135	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	AM Modulation (CF :2 MHz to 3.5 GHz) (Mod Rate :50 Hz to 100 kHz)	Using Signal Analyser by Direct Method	5 % to 99 %	0.24 % to 1.1 %
136	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	Displayed Average Noise Level @ 1 MHz to 44 GHz	Using Signal Analyser & Signal Generator by Direct /Comparison Method	-90 dBm to -160 dBm	2.5 dB
137	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	FM Modulation (CF :2 MHz to 3.5 GHz) (Mod Rate :20 Hz to 50 kHz)	Using Signal Analyser by Direct Method	200 kHz to 400 kHz	3.1 kHz to 6.3 kHz
138	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	Frequency	Using Signal Analyser by Direct Method	9 kHz to 40 GHz	0.0012 % to 0.000022 %



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139	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	Microwave Power @ 10 MHz to 18 GHz	Using Power sensor by Direct Method	-60 dBm to 20 dBm	0.52 dB
140	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	Microwave Power @ 100 kHz to 22 GHz	Using Signal Analyser by Direct Method	-60 dBm to 13 dBm	0.5 dB
141	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	Microwave Power @ 26.5 GHz to 40 GHz	Using Signal Analyser by Direct Method	-135 dBm to 21 dBm	1.35 dB to 1.14 dB
142	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	Microwave Power @ 300 kHz to 26.5 GHz	Using Signal Analyser by Direct Method	-135 dBm to 21 dBm	1.16 dB to 1.36 dB
143	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	Phase Noise @ 0.1 kHz to 1MHz	Using Signal Analyser by Direct Method	-80 dBc/Hz to -150 dBc/Hz	1.43 dB to 2.52 dB



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144	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	PM Modulation (CF :2 MHz to 3.5 GHz) (Mod Rate :50 Hz to 50 kHz)	Using Signal Analyser by Direct Method	0.3 rad to 10 rad	0.009 rad to 0.43 rad
145	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	AM Modulation (CF :1 MHz to 5 GHz) (Mod Rate :50 Hz to 100 kHz)	Using Signal Generator by Direct Method	5 % to 99 %	1.2 % to 1.95 %
146	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	FM Modulation (CF :1 MHz to 3.5 GHz) (Mod Rate :20 Hz to 50 kHz)	Using Signal Generator by Direct Method	200 kHz to 400 kHz	2.8 kHz to 5.5 kHz
147	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	Frequency	Using Signal Generator by Direct Method	9 kHz to 40 GHz	0.000021 % to 0.000019 %
148	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	Harmonic Spurious 2nd Harmonic Fund. Freq. :1 MHz to 20 GHz	Using Signal Generator by Direct Method	-25 dBc to -100 dBc	1.43 dB to 2.34 dB



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149	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	Harmonic Spurious3rd Harmonic Fund. Freq. :1 MHz to 10 GHz	Using Signal Generator by Direct Method	-25 dBc to -100 dBc	2.3 dB to 3.75 dB
150	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	Microwave Power @3 GHz to 20 GHz	Using Signal Generator by Direct Method	-135 dBm to -90 dBm	0.56 dB
151	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	Microwave Power @3 GHz to 40 GHz	Using Signal Generator by Direct Method	-90 dBm to 15 dBm	0.56 dB to 0.45 dB
152	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	Microwave Power @9 kHz to 3 GHz	Using Signal Generator by Direct Method	-135 dBm to 20 dBm	0.42 dB to 0.56 dB
153	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	PM Modulation (CF :1 MHz to 3.5 GHz) (Mod Rate :50 Hz to 50 kHz)	Using Signal Generator by Direct Method	0.3 rad to 10 rad	0.015 rad to 0.14 rad



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154	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	SSB Phase Noise @ 250 MHz to 20 GHz	Using Signal Generator by Direct Method	-90 dBc/Hz to -140 dBc/Hz	2.5 dB
155	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	Sub-Harmonic Spurious Multiple of fund. Freq by 0.5Fund. Freq. :1.6 GHz to 40 GHz	Using Signal Generator by Direct Method	-50 dBc to -130 dBc	3.8 dB to 1.8 dB
156	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	RTD	Using 61/2 DMM by Direct Method	-200 ° C to 800 ° C	0.12 ° C
157	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "B Type"	Using MPC by Direct Method	1000 ° C to 1820 ° C	0.4 ° C
158	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "B Type"	Using MPC by Direct Method	600 ° C to 1000 ° C	0.48 ° C



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159	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "C Type"	Using MPC by Direct Method	1500 ° C to 2315 ° C	0.71 ° C
160	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "C Type"	Using MPC by Direct Method	200 ° C to 1500 ° C	0.41 ° C
161	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "E Type"	Using MPC by Direct Method	-200 ° C to 1000 ° C	0.28 ° C
162	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "J Type"	Using MPC by Direct Method	-200 ° C to 500 ° C	0.08 ° C
163	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "J Type"	Using MPC by Direct Method	500 ° C to 1200 ° C	0.08 ° C
164	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "K Type"	Using MPC by Direct Method	-200 ° C to 1370 ° C	0.1 ° C



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165	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "L Type"	Using MPC by Direct Method	-200 ° C to 900 ° C	0.19 ° C
166	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "N Type"	Using MPC by Direct Method	-200 ° C to 1300 ° C	0.069 ° C
167	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "R Type"	Using MPC by Direct Method	20 ° C to 1760 ° C	0.19 ° C
168	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "S Type"	Using MPC by Direct Method	20 ° C to 1760 ° C	0.13 ° C
169	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "T Type"	Using MPC by Direct Method	-200 ° C to 400 ° C	0.064 ° C
170	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "U Type"	Using MPC by Direct Method	-200 ° C to 600 ° C	0.204 ° C



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171	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	RTD	Using MPC by Direct Method	100 ° C to 800 ° C	0.21 ° C
172	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	RTD	Using MPC by Direct Method	-200 ° C to 100 ° C	0.08 ° C
173	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "B Type"	Using MPC by Direct Method	1000 ° C to 1820 ° C	0.31 ° C
174	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "B Type"	Using MPC by Direct Method	600 ° C to 1000 ° C	0.4 ° C
175	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "C Type"	Using MPC by Direct Method	1500 ° C to 2315 ° C	0.71 ° C
176	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "C Type"	Using MPC by Direct Method	200 ° C to 1500 ° C	0.41 ° C



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177	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "E Type"	Using MPC by Direct Method	-200 ° C to 1000 ° C	0.092 ° C
178	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "J Type"	Using MPC by Direct Method	-200 ° C to 500 ° C	0.08 ° C
179	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "J Type"	Using MPC by Direct Method	500 ° C to 1200 ° C	0.067 ° C
180	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "K Type"	Using MPC by Direct Method	-200 ° C to 1370 ° C	0.1 ° C
181	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "L Type"	Using MPC by Direct Method	-200 ° C to 900 ° C	0.19 ° C
182	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "N Type"	Using MPC by Direct Method	-200 ° C to 1300 ° C	0.056 ° C



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183	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "R Type"	Using MPC by Direct Method	20 ° C to 1760 ° C	0.092 ° C
184	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "S Type"	Using MPC by Direct Method	20 ° C to 1760 ° C	0.061 ° C
185	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "T Type"	Using MPC by Direct Method	-200 ° C to 400 ° C	0.056 ° C
186	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "U Type"	Using MPC by Direct Method	-200 ° C to 600 ° C	0.2 ° C
187	ELECTRO-TECHNICAL-TIME & FREQUENCY (Measure)	Frequency	Using 6½ DMM by Direct Method	100 Hz to 300 kHz	0.041 % to 0.023 %
188	ELECTRO-TECHNICAL-TIME & FREQUENCY (Measure)	Frequency	Using 6½ DMM by Direct Method	3 Hz to 100 Hz	0.23 % to 0.041 %



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189	ELECTRO-TECHNICAL-TIME & FREQUENCY (Measure)	Time	Using Digital Timer by Comparison Method	0.1 s to 60 s	0.01 s to 0.02 s
190	ELECTRO-TECHNICAL-TIME & FREQUENCY (Measure)	Time	Using Digital Timer by Comparison Method	1 hr to 24 hr	0.12 s to 3.3 s
191	ELECTRO-TECHNICAL-TIME & FREQUENCY (Measure)	Time	Using Digital Timer by Comparison Method	60 s to 1 hr	0.02 s to 0.12 s
192	ELECTRO-TECHNICAL-TIME & FREQUENCY (Source)	Frequency	Using MPC by Direct Method	0.1 Hz to 100 kHz	5.81 % to 0.006 %
193	ELECTRO-TECHNICAL-TIME & FREQUENCY (Source)	Frequency	Using MPC by Direct Method	100 kHz to 2 MHz	0.006 % to 0.029 %
194	MECHANICAL-ACCELERATION AND SPEED	RPM Calibrator/Tachometer Calibrator/RPM Source	Using Digital Tachometer by Direct Method	10 rpm to 1000 rpm	0.48 rpm



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195	MECHANICAL-ACCELERATION AND SPEED	RPM Calibrator/Tachometer Calibrator/RPM Source	Using Digital Tachometer by Direct Method	1000 rpm to 10000 rpm	1.3 rpm
196	MECHANICAL-ACCELERATION AND SPEED	RPM Calibrator/Tachometer Calibrator/RPM Source	Using Digital Tachometer by Direct Method	10000 rpm to 50000 rpm	3.2 rpm
197	MECHANICAL-ACCELERATION AND SPEED	RPM Calibrator/Tachometer Calibrator/RPM Source	Using Digital Tachometer by Direct Method	50000 rpm to 90000 rpm	3.2 rpm
198	MECHANICAL-ACCELERATION AND SPEED	Tachometer (Contact)	Using Digital Tachometer and Tachometer Calibrator by Comparison Method	10 rpm to 1000 rpm	0.46 rpm
199	MECHANICAL-ACCELERATION AND SPEED	Tachometer (Contact)	Using Digital Tachometer and Tachometer Calibrator by Comparison Method	1000 rpm to 6000 rpm	0.86 rpm
200	MECHANICAL-ACCELERATION AND SPEED	Tachometer (Non Contact)	Using Digital Tachometer and Tachometer Calibrator by Comparison Method	10 rpm to 1000 rpm	0.60 rpm



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201	MECHANICAL-ACCELERATION AND SPEED	Tachometer (Non Contact)	Using Digital Tachometer and Tachometer Calibrator by Comparison Method	1000 rpm to 10000 rpm	1.2 rpm
202	MECHANICAL-ACCELERATION AND SPEED	Tachometer (Non Contact)	Using Digital Tachometer and Tachometer Calibrator by Comparison Method	10000 rpm to 50000 rpm	3.2 rpm
203	MECHANICAL-ACCELERATION AND SPEED	Tachometer (Non Contact)	Using Digital Tachometer and Tachometer Calibrator by Comparison Method	50000 rpm to 90000 rpm	3.6 rpm
204	MECHANICAL-ACOUSTICS	Sound Level Meter @ 1 kHz	Using Sound Level Calibrator by Direct Method	94 dB	0.6 dB
205	MECHANICAL-ACOUSTICS	Sound Level Meter@ 1 kHz	Using Sound Level Calibrator by Direct Method	114 dB	0.60 dB



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206	MECHANICAL-PRESSURE INDICATING DEVICES	Absolute Pressure(Pneumatic) : Absolute pressure gauges / Barometers / Manometers / Absolute pressure calibrators, Pressure Switches, Pressure Transducers / Transmitters	Using Absolute Pressure calibrator with Digital Multimeter & Pneumatic Hand Pump by Comparison Method as per DKD-R 6-1	0.2 bar(a) to 7 bar(a)	0.0015 bar(a)
207	MECHANICAL-PRESSURE INDICATING DEVICES	Low Pressure (Pneumatic): Magnehelic gauges / Low Pressure gauges/Low pressure Transmitters and Switches	Using Digital Pressure Gauge, Digital Multimeter & Pneumatic Hand Pump by Comparison Method DKD R-6-1	0 to 200 mbar	0.064 mbar
208	MECHANICAL-PRESSURE INDICATING DEVICES	Negative Pressure: Magnehelic gauges/ Low Pressure gauges/Low pressure Transmitters and switches	Using Digital Pressure Gauge, Digital Multimeter & Pneumatic Hand Pump by Comparison Method DKD R-6-1	(-)200 mbar to 0 mbar	0.064 mbar



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209	MECHANICAL-PRESSURE INDICATING DEVICES	Negative pressure: Vacuum Gauges, Vacuum Calibrators, Pressure Switches, Pressure Transmitters	Using Digital Pressure Gauge, Digital Multimeter & Pneumatic Hand Pump by Comparison Method DKD R-6-1	(-)0.95 bar to 0 bar	0.0003 bar
210	MECHANICAL-PRESSURE INDICATING DEVICES	Pressure (Hydraulic): Pressure gauges, Pressure Calibrators, Pressure Switches , Pressure Transmitters	Using Digital Pressure Gauge, Digital Multimeter & Hydraulic Comparator by Comparison Method DKD R-6-1	0 to 200 bar	0.038 bar
211	MECHANICAL-PRESSURE INDICATING DEVICES	Pressure (Hydraulic): Pressure gauges, Pressure Calibrators, Pressure Switches , Pressure Transmitters	Using Digital Pressure Gauge, Digital Multimeter & Hydraulic Comparator by Comparison Method DKD R-6-1	0 to 350 bar	0.1 bar
212	MECHANICAL-PRESSURE INDICATING DEVICES	Pressure (Hydraulic): Pressure gauges, Pressure Calibrators, Pressure Switches , Pressure Transmitters	Using Digital Pressure Gauge, Digital Multimeter & Hydraulic Comparator by Comparison Method DKD R-6-1	0 to 70 bar	0.011 bar



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213	MECHANICAL-PRESSURE INDICATING DEVICES	Pressure (Hydraulic): Pressure gauges, Pressure Calibrators, Pressure Switches , Pressure Transmitters	Using Digital Pressure Gauge, Digital Multimeter & Hydraulic Comparator by Comparison Method DKD R-6-1	0 to 700 bar	0.11 bar
214	MECHANICAL-PRESSURE INDICATING DEVICES	Pressure(Pneumatic) : Pressure gauges, Pressure Calibrators, Pressure Switches, Pressure Transmitters	Using Digital Pressure Gauge, Digital Multimeter & Pneumatic Hand Pump by Comparison Method DKD R-6-1	0 to 10 bar	0.0026 bar
215	MECHANICAL-PRESSURE INDICATING DEVICES	Pressure(Pneumatic) : Pressure gauges, Pressure Calibrators, Pressure Switches, Pressure Transmitters	Using Digital Pressure Gauge, Digital Multimeter & Pneumatic Hand Pump by Comparison Method DKD R-6-1	0 to 2 bar	0.0005 bar
216	MECHANICAL-PRESSURE INDICATING DEVICES	Pressure(Pneumatic) : Pressure gauges, Pressure Calibrators, Pressure Switches, Pressure Transmitters	Using Digital Pressure Gauge, Digital Multimeter & Pneumatic Hand Pump by Comparison Method DKD R-6-1	0 to 40 bar	0.0096 bar



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217	THERMAL-SPECIFIC HEAT & HUMIDITY	Dew Point Temperature Indicator with Sensor, Transmitter (20 %rh to 95 % rh)	Using Humidity Chamber, Dew Point Temperature Sensor with Indicator and Multifunction Calibrator by Comparison Method	(-)10 °C to 20 °C	1.0 °C
218	THERMAL-SPECIFIC HEAT & HUMIDITY	Humidity Chamber (Multipositions) @ (25 °C to 50 °C)	Using Temperature & Humidity Data Loggers (minimum 3 Nos) by Comparison Method	10 % rh to 95 % rh	2.0 % rh
219	THERMAL-SPECIFIC HEAT & HUMIDITY	Humidity Chamber (Multipositions) @ (50% RH)	Using Temperature & Humidity Data Loggers(minimum 3 Nos) by Comparison Method	10 °C to 60 °C	0.5 °C
220	THERMAL-SPECIFIC HEAT & HUMIDITY	Thermo Hygrometer, Humidity Transmitter, Humidity Indicator with Sensor @ (10 °C to 60 °C)	Using Humidity Chamber with Digital Temperature & Humidity Indicator with Sensor by Comparison Method	10 %rh to 95 %rh	1.6 %rh
221	THERMAL-SPECIFIC HEAT & HUMIDITY	Thermo Hygrometer, Humidity Transmitter, Humidity Indicator with Sensor @ (50 % rh)	Using Humidity Chamber with Digital Temperature & Humidity Indicator with Sensor and PRT with Indicator by Comparison Method	6 °C to 60 °C	0.29 °C



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222	THERMAL-TEMPERATURE	Black Body Source, IR Calibrator	Using Non Contact IR Thermometer (Emissivity: 0.95) by Comparison Method	(-)30 °C to 100 °C	1.2 °C
223	THERMAL-TEMPERATURE	Black Body Source, IR Calibrator	Using Non Contact IR Thermometer (Emissivity: 0.95) by Comparison Method	100 °C to 500 °C	1.8 °C
224	THERMAL-TEMPERATURE	Infrared, Non-Contact Thermometer, Pyrometer, Thermal Imager (Temp. only)	Using Non-Contact IR Thermometer (Emissivity: 0.95) and Black Body Source By Comparison Method	(-)20 °C to 50 °C	1.57 °C
225	THERMAL-TEMPERATURE	Infrared, Non-Contact Thermometer, Pyrometer, Thermal Imager (Temp. only)	Using Non-Contact IR Thermometer (Emissivity: 0.95) and Black Body Source By Comparison Method	50 °C to 500 °C	2.11 °C
226	THERMAL-TEMPERATURE	RTD with /without indicator, Thermocouple with/without indicator, Temperature Gauges, Temperature Transmitter with/without indicator	Using Standard PRT with Indicator and Dry Temperature Bath and 6.5 digit DMM By Comparison Method	(-)30 °C to 100 °C	0.11 °C



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227	THERMAL-TEMPERATURE	RTD with /without indicator, Thermocouple with/without indicator, Temperature Gauges, Temperature Transmitter with/without indicator	Using Standard PRT with Indicator and Dry Temperature Bath and 6.5 digit DMM By Comparison Method	100 °C to 650 °C	0.13 °C
228	THERMAL-TEMPERATURE	Thermocouple with/without indicator, Temperature Transmitter with/without indicator	Using Standard 'S' Type Thermocouple with Indicator and Dry Temperature Bath and DMM By Comparison Method	650 °C to 1200 °C	1.92 °C



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Site Facility					
1	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current (50 Hz to 1 kHz)	Using 6½ DMM by Direct Method	1 A to 3 A	3.5 % to 0.56 %
2	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current (50 Hz to 1 kHz)	Using 6½ DMM by Direct Method	1 mA to 100 mA	0.2 % to 0.31 %
3	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current (50 Hz to 1 kHz)	Using 6½ DMM by Direct Method	100 µA to 1 mA	1.02 % to 0.2 %
4	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current (50 Hz to 1 kHz)	Using 6½ DMM by Direct Method	100 mA to 1 A	0.58 % to 3.5 %



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5	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Current (50 Hz to 1 kHz)	Using 6½ DMM by Direct Method	30 µA to 100 µA	1.74 % to 1.02 %
6	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC High Voltage @50 Hz	Using High Voltage Divider with kV Meter by Comparison Method	1 kV to 100 kV	2.38 % to 2.37 %
7	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC High Voltage @50 Hz	Using High Voltage Divider with kV Meter and High Voltage Source by Comparison Method	1 kV to 30 kV	2.0 %
8	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Voltage (50 Hz to 1 kHz)	Using 6½ DMM by Direct Method	1 mV to 100 mV	2.59 % to 0.087 %
9	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Measure)	AC Voltage (50 Hz to 1 kHz)	Using 6½ DMM by Direct Method	100 mV to 750 V	0.087 % to 0.12 %



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10	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Active Power (1Ph, 2W) @ (50 Hz) (30 V to 480 V , 0.05 A to 20 A,(0.1 Lead/Lag to UPF)	Using MPC by Direct Method	0.15 W to 9.6 kW	3.8 % to 0.19 %
11	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current (>1 kHz to 5 kHz)	Using MPC by Direct Method	1 A to 10 A	0.085 % to 0.15 %
12	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current (>1 kHz to 5 kHz)	Using MPC by Direct Method	10 µA to 100 µA	2.65 % to 0.11 %
13	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current (>1 kHz to 5 kHz)	Using MPC by Direct Method	10 A to 30 A	0.15 % to 0.5 %
14	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current (>1 kHz to 5 kHz)	Using MPC by Direct Method	100 µA to 1 A	0.11 % to 0.085 %
15	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current (45 Hz to 1 kHz)	Using MPC by Direct Method	1 A to 3 A	0.06 % to 0.098 %



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16	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current (45 Hz to 1 kHz)	Using MPC by Direct Method	10 µA to 100 µA	2.6 % to 0.11 %
17	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current (45 Hz to 1 kHz)	Using MPC by Direct Method	100 µA to 1 A	0.11 % to 0.06 %
18	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current (45 Hz to 1 kHz)	Using MPC by Direct Method	3 A to 30 A	0.098 % to 0.101 %
19	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Current (50 Hz)	Using MPC and Current Coil by Direct Method	30 A to 1000 A	0.49 % to 0.37 %
20	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage (>1 kHz to 10 kHz)	Using MPC by Direct Method	300 V to 1000 V	0.021 % to 0.034 %
21	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage (>1 kHz to 20 kHz)	Using MPC by Direct Method	1 mV to 10 mV	0.84 % to 0.095 %



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22	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage (>1 kHz to 20 kHz)	Using MPC by Direct Method	10 mV to 300 V	0.095 % to 0.022 %
23	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage (10 Hz to 1 kHz)	Using MPC by Direct Method	1 mV to 10 mV	0.84 % to 0.095 %
24	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage (10 Hz to 1 kHz)	Using MPC by Direct Method	10 mV to 300 V	0.095 % to 0.022 %
25	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	AC Voltage (40 Hz to 1 kHz)	Using MPC by Direct Method	300 V to 1000 V	0.021 % to 0.034 %
26	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Capacitance @ 1 kHz	Using Decade Capacitance box By Direct Method	10 pF to 100 µF	1.45 % to 1.46 %
27	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Inductance @ 1 kHz	Using Decade Inductance box By Direct Method	1 mH to 10 H	1.54 % to 1.45 %



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28	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Phase Angle	Using MPC by Direct Method	0 ° to 180 °	0.12 °
29	ELECTRO-TECHNICAL-Alternating Current (< 1 GHz) (Source)	Power Factor	Using MPC by Direct Method	0.1 PF (Lead/Lag) to UPF to	0.001 PF
30	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Current	Using 6½ DMM by Direct Method	1 µA to 1 mA	0.27 % to 0.062 %
31	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Current	Using 6½ DMM by Direct Method	1 A to 3 A	0.06 % to 0.14 %
32	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Current	Using 6½ DMM by Direct Method	1 mA to 100 mA	0.061 % to 0.031 %
33	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Current	Using Shunt and DMM by VI Method	100 A to 1200 A	0.5 %



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34	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Current	Using 6½ DMM by Direct Method	100 mA to 1 A	0.031 % to 0.06 %
35	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Current	Using Shunt and DMM by VI Method	30 A to 100 A	0.5 %
36	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC High Voltage	Using High Voltage Divider with kV Meter by Comparison Method	1 kV to 100 kV	2.05 % to 1.98 %
37	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC High Voltage	Using High Voltage Divider with kV Meter and High Voltage Source by Comparison Method	1 kV to 40 kV	2.0 %
38	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Voltage	Using 6½ DMM by Direct Method	1 mV to 100 mV	0.42 % to 0.008 %
39	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	DC Voltage	Using 6½ DMM by Direct Method	100 mV to 1000 V	0.008 % to 0.0057 %



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40	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	Resistance (4W)	Using 6½ DMM by Direct Method	0.1 ohm to 10 kohm	0.42 % to 0.059 %
41	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	Resistance (4W)	Using 6½ DMM by Direct Method	10 kohm to 100 kohm	0.059 % to 0.016 %
42	ELECTRO-TECHNICAL-DIRECT CURRENT (Measure)	Resistance 2W	Using 6½ DMM by Direct Method	100 kohm to 100 Mohm	0.016 % to 1.32 %
43	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MPC by Direct Method	1 µA to 100 µA	1.01 % to 0.021 %
44	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MPC by Direct Method	1 A to 10 A	0.018 % to 0.048 %
45	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MPC by Direct Method	10 A to 30 A	0.048 % to 0.10 %



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46	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MPC by Direct Method	100 µA to 100 mA	0.021 % to 0.011 %
47	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MPC by Direct Method	100 mA to 1 A	0.011 % to 0.018 %
48	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Current	Using MPC and Current Coil by Direct Method	30 A to 1000 A	0.42 % to 0.34 %
49	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Power (10 mV to 1000 V, 10 mA to 30 A)	Using MPC by Direct Method	100 mW to 30 kW	3.8 % to 0.37 %
50	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Voltage	Using MPC by Direct Method	1 mV to 100 mV	0.12 % to 0.003 %
51	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Voltage	Using MPC by Direct Method	10 V to 1000 V	0.0011 % to 0.002 %



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52	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	DC Voltage	Using MPC by Direct Method	100 mV to 10 V	0.003 % to 0.0011 %
53	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance (2-Wire) @ 1 kV to 5 kV	Using Decade Resistance Box By Direct Method	10 Mohm to 1 Tohm	2.1 % to 3.8 %
54	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance (2/4-Wire)	Using Decade Resistance Box By Direct Method	1 ohm to 10 ohm	0.06 % to 0.03 %
55	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance (2/4-Wire)	Using Decade Resistance Box By Direct Method	10 mohm to 1 ohm	1.16 % to 0.007 %
56	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance (2/4-Wire)	Using Decade Resistance Box By Direct Method	10 Mohm to 100 Mohm	0.61 %
57	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance (2/4-Wire)	Using Decade Resistance Box By Direct Method	10 ohm to 10 Mohm	0.03 % to 0.61 %



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58	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance (2/4-Wire)	Using Decade Resistance Box By Direct Method	100 Mohm to 10 Gohm	0.61 % to 0.83 %
59	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance(2W)	Using MPC by Direct Method	10 Mohm to 100 Mohm	0.0054 % to 0.049 %
60	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance(2W)	Using MPC by Direct Method	100 kohm to 10 Mohm	0.0029 % to 0.0054 %
61	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance(2W)	Using MPC by Direct Method	100 Mohm to 1000 Mohm	0.049 % to 0.6 %
62	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance(4W/2W)	Using MPC by Direct Method	1 ohm to 10 ohm	0.12 % to 0.015 %
63	ELECTRO-TECHNICAL-DIRECT CURRENT (Source)	Resistance(4W/2W)	Using MPC by Direct Method	10 ohm to 100 kohm	0.015 % to 0.0029 %



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64	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope (AC Amplitude @1 kHz to 10 kHz)	Using MPC by Direct Method	1 mV to 120 V	0.99 % to 0.1 %
65	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope (Bandwidth)	Using Signal Generators by Direct Method	1 GHz to 4 GHz	0.46 dB to 0.5 dB
66	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope (Bandwidth)	Using MPC by Direct Method	50 kHz to 600 MHz	1.62 % to 3.37 %
67	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope (Bandwidth)	Using MPC by Direct Method	600 MHz to 1 GHz	3.37 % to 5.7 %
68	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope (DC Amplitude)	Using MPC by Direct Method	5 mV to 120 V	0.99 % to 0.059 %
69	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope (Time Marker)	Using Signal Generators by Direct Method	0.5 ns to 20 ns	0.004 % to 0.00098 %



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70	ELECTRO-TECHNICAL-ELECTRICAL EQUIPMENT (Source)	Oscilloscope (Time Marker)	Using MPC by Direct Method	20 ns to 2 s	0.029 % to 0.00042 %
71	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Antenna Factor (9 kHz to 30 MHz)	Using VectorNetwork Analyzer, RF Reference Sourceand Signal Analyzeras per ANSI C63.5	- 5 dB to 96 dB	0.69 dB
72	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Automotive Transient Pulses 1,2a,2b,3a,3b,4,5 : Pulse Width/Duration	Using Digital Oscilloscope, Differential Probe, passive voltage probe and load resistors by Direct Method as per ISO 7637-2, SAE J-1113-11	50 ns to 10 s	0.23 %
73	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Automotive Transient Pulses 1,2a,2b,3a,3b,4,5 : Rise Time/Fall Time	Using Digital Oscilloscope, Differential Probe, passive voltage probe and load resistors by Direct Method as per ISO 7637-2, SAE J-1113-11	1 ns to 100 ms	2.32 %



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74	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Automotive Transient Pulses 1,2a,2b,3a,3b,4,5 : Amplitude	Using Digital Oscilloscope & Differential Probe by Direct Method as per ISO 7637-2, SAE J-1113-11	-600 V to 400 V	2.92 %
75	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Capacitive coupling clamp - Pulse Duration	Using Digital Oscilloscope & Load Resistor as per ISO 7637-3 by Direct Method	150 ns	0.08 %
76	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Capacitive coupling clamp - Rise Time	Using Digital Oscilloscope & Load Resistor as per ISO 7637-3 by Direct Method	5 ns	1.63 %
77	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Capacitive coupling clamp - Voltage Amplitude	Using Digital Oscilloscope & Load Resistor as per ISO 7637-3 by Direct Method	-400 V to 400 V	3 %
78	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Combination wave surge test system (Generator, CDN output) a)Voltage Amplitude	Using Digital Storage Oscilloscope, High Voltage Differential Probe as per IEC 61000-4-5 by Direct Method	±0.25 kV to ±7.0 kV	3.84 %



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79	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Combination wave surge test system (Generator, CDN output) b)Voltage front time	Using Digital Storage Oscilloscope, High Voltage Differential Probe as per IEC 61000-4-5 by Direct Method	1.2 μ s	0.09 μ s
80	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Combination wave surge test system (Generator, CDN output) c)Voltage Duration	Using Digital Storage Oscilloscope, High Voltage Differential Probe as per IEC 61000-4-5 by Direct Method	50 μ s	0.03 μ s
81	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Combination wave surge test system (Generator, CDN output) d)current amplitude	Using Digital Storage Oscilloscope, Current probe as per IEC 61000-4-5 by Direct Method	$\pm$ 20.83 A to $\pm$ 3.5 kA	1.96 %
82	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Combination wave surge test system (Generator, CDN output) e)current front time	Using Digital Storage Oscilloscope, Current probe as per IEC 61000-4-5 by Direct Method	2.5 μ s to 8 μ s	1.64 %



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83	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Combination wave surge test system (Generator, CDN output) f) current Duration	Using Digital Storage Oscilloscope, Current probe as per IEC 61000-4-5 by Direct Method	20 μ s to 25 μ s	0.08 %
84	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Coupling Factor/Coupling loss /Decoupling of common mode Disturbance /Insertion loss /RF Attenuation/Isolation /Voltage Division Factor (EM Clamp,SWR Bridge,Directional Coupler) 9 kHz to 4.5 GHz	Using Vector network analyzer by direct method	0 dB to 80 dB	0.69 dB
85	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	CouplingFactor/loss/ CommonModelmped ance/Directivity/Inse rtion loss/RFAttenuation/Is olation/VDF (20 Hz to 9 kHz)	Using Signal Generator, Function Generator Spectrum Analyzer by Direct Method	1 dB to 60 dB	0.23 dB to 1.78 dB



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86	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	CouplingFactor/loss/ CommonModelmpedance/Directivity/Inser tion loss/RFAttenuation/Isolation/VDF (9 kHz to 20 GHz)	Using Vector network analyzer by Direct method	0.1 dB to 90 dB	0.74 dB
87	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Damped oscillatory magnetic field strength generator with Standard Coil - oscillation Period @ 100 kHz	Using Digital Storage Oscilloscope, Current probe by Direct Method as per IEC 61000-4-10:2016	10 μ s	2.5 %
88	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Damped oscillatory magnetic field strength generator with Standard Coil - Peak current & decaying (Pk5) & (Pk10)	Using Digital Storage Oscilloscope, Current probe by Direct Method as per IEC 61000-4-10:2016	5 A to 100 A	3.91 % to 2.03 %
89	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Damped oscillatory magnetic field strength generator with Standard Coil - Repetition time @1 MHz	Using Digital Storage Oscilloscope, Current probe by Direct Method as per IEC 61000-4-10:2016	2.5 ms	3.3 %



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90	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Damped oscillatory magnetic field strength generator with Standard Coil - Oscillation Period @ 1 MHz	Using Digital Storage Oscilloscope, Current probe by Direct Method as per IEC 61000-4-10:2016	1 μ s	5.05 %
91	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Damped oscillatory magnetic field strength generator with Standard Coil: Repetition time @ 100 kHz	Using Digital Storage Oscilloscope, Current probe by Direct Method as per IEC 61000-4-10:2016	25 ms	3.3 %
92	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Damped Oscillatory wave Generator (Voltage Amplitude) (Voltage Decay) Decay in Peak 10 to be 50% of peak 1 value	Using Voltage Differential Probe & Digital Oscilloscope as per IEC 61000-4-18 by Direct Method	± 0.25 kV to ± 4.0 kV	2.81 % to 3.9 %
93	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Damped Oscillatory wave Generator - Slow and Fast(Repetition Rate)	Using Voltage Differential Probe & Digital Oscilloscope as per IEC 61000-4-18 by Direct Method	40 Hz, 400 Hz, 5 kHz	0.06 % to 0.13 %



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94	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Damped Oscillatory wave Generator-Slow and Fast (Current Amplitude)	Using Current Probe & Digital Oscilloscope as per IEC 61000-4-18 by Direct Method	±1.25 A to ±12.5 A	1.88 % to 1.95 %
95	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Damped Oscillatory wave Generator-Slow and Fast (Oscillation Frequency)	Using Voltage Differential Probe & Digital Oscilloscope as per IEC 61000-4-18 by Direct Method	100 kHz, 1 MHz, 3 MHz, 10 MHz and 30 MHz	1.21 % to 0.38 %
96	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Damped Oscillatory wave Generator-Slow and Fast (Rise Time)	Using Voltage Differential Probe & Digital Oscilloscope as per IEC 61000-4-18 by Direct Method	5 ns to 75 ns	3.31 % to 0.23 %
97	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrical fast transient test system (Generator output) Burst Period	Using Digital Storage Oscilloscope with Load Resistor 50 ohm & 1000 ohm as per IEC 61000-4-4 by Direct Method	300 ms	0.19 ms
98	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrical fast transient test system (Generator output) e) Burst Duration (2.5 kHz/5 kHz/100 kHz/1000 kHz)	Using Digital Storage Oscilloscope with Load Resistor 50 ohm & 1000 ohm as per IEC 61000-4-4 by Direct Method	0.75 ms to 15 ms	0.05 ms



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99	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrical fast transient test system (Generator output, Capacitive Clamp) d)Repetition frequency (inverse)	Using Digital Storage Oscilloscope with Load Resistor 50 ohm & 1000 ohm as per IEC 61000-4-4 by Direct Method	2.5,5,100,1000 kHz	0.15 %
100	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrical fast transient test system (Generator, CDN output, Capacitive Clamp) a) Pulse Amplitude	Using Digital Storage Oscilloscope with Load Resistor 50 ohm & 1000 ohm as per IEC 61000-4-4 by Direct Method	±125 V to ±5.5 kV	3 %
101	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrical fast transient test system (Generator, CDN output, Capacitive Clamp) Pulse Rise time	Using Digital Storage Oscilloscope with Load Resistor 50 ohm & 1000 ohm as per IEC 61000-4-4 by Direct Method	5 ns to 5.5 ns	0.17 ns
102	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrical fast transient test system (Generator, CDN output, Capacitive Clamp) Pulse width	Using Digital Storage Oscilloscope with Load Resistor 50 ohm & 1000 ohm as per IEC 61000-4-4 by Direct Method	45 ns to 50 ns	0.17 ns
103	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrostatic Discharge Generator a)First peak current (± 2.0 kV TO ±30 kV)	Using Digital Storage Oscilloscope , ESD Target as per IEC 61000-4-2, SAE J1113-13, ISO 10605	±6.38 A to ±146.25 A	6.64 %



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104	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrostatic Discharge Generator b)Rise time	Using Digital Storage Oscilloscope , ESD Target as per IEC 61000-4-2, SAE J1113-13, ISO 10605	0.6 ns to 1 ns	11.44 %
105	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrostatic Discharge Generator c) Current @ 30 ns/65ns/180ns/400ns (± 2.0 kV TO ±30 kV)	Using Digital Storage Oscilloscope , ESD Target as per IEC 61000-4-2, SAE J1113-13, ISO 10605	±0.385 A to ±78 A	6.27 %
106	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrostatic Discharge Generator d) Current @ 60 ns/130ns/360ns/800ns (± 2.0 kV TO ±30 kV)	Using Digital Storage Oscilloscope , ESD Target as per IEC 61000-4-2, SAE J1113-13, ISO 10605	±0.15 A to ±39 A	6.23 %
107	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Electrostatic Discharge Generator-Generator DC output voltage	Using High voltage probe, Dual display Multimeter as per IEC 61000- 4-2 , SAE J1113-13 ISO 10605	±1 kV to ±30 kV	3.95 %
108	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	ElectrostaticDischarge Generator)Second peak current(± 2.0 kV TO ±30 kV)	Using Digital Storage Oscilloscope ESD Target as per Direct Method as per IEC 61000-4- 2:2025	±2.7 A to ±94.5 A	6.64 %



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109	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Impedance 9 kHz to 400 MHz	Using Vector network analyzer by direct method	1 ohm to 300 ohm	4 %
110	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Impulse / Surge(Peak Voltage)	Using HV Probe with Oscilloscope By Direct Method	±0.1 kV to ±20 kV	3.8 % to 4.1 %
111	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Impulse magneticField Generator with Standard Coil - Front time	Using DigitalStorage Oscilloscope,Current probe byDirect Method as perIEC 61000-4- 9:2016	8 µs	6.05 %
112	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Impulse magneticField Generator with Standard Coil - Peak current	Using DigitalStorage Oscilloscope,Current probe byDirect Method as perIEC 61000-4- 9:2016	86 A/m to 2200 A/m	6.05 %
113	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Impulse magneticField Generator withStandard Coil - Duration	Using DigitalStorage Oscilloscope,Current probe byDirect Method as perIEC 61000-4- 9:2016	20 µs	5.25 %
114	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Longitudinal conversion loss (Impedance stabilization Network) 9 kHz to 30 MHz	Using Vector network analyzer by direct method AS Per CISPR 22,CISPR 32	0 dB to 60 dB	0.69 dB



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115	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Low frequency Transfer impedance/ Resistance Target	Using MPC and 6½ DMM by IEC 61000 4-2 & ISO 10605	2 ohm	2.8 %
116	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Phase Angle (9 kHz to 400 MHz)	Using Vector network analyzer by direct method CISPR 16-1-2	-90 ° to 90 °	1.1 °
117	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Phase Shifting (Surge/ Ringwave/ Dips Generator)	Using Voltage Differential Probe & Digital Oscilloscope as per IEC 61000-4-5, IEC 61000-4-12, IEC 61000-4-11 by Direct Method	0 ° to 360 °	0.08 ° to 0.23 °
118	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Power Frequency Magnetic Field Generator with Standard Coil - Magnetic field strength @50 Hz	Using Flexible Current probe with Clamp meter by Direct Method As per IEC 61000-4-8:2009	100 A to 1000 A	3.59 % to 3.5 %
119	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Return loss/ VSWR/Reflection coefficient (Transient limiter, Directional coupler, Attenuator, Cable, Pre amplifier, Terminator) 9 kHz to 4.5 GHz	Using Vector network analyzer by Direct Method	1 dB to 46 dB	0.69 dB



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120	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Return loss/VSWR/Reflection Co-efficient (9 kHz to 20 GHz)	Using Vector network analyzer by Direct method	0.1 dB to (-) 60 dB	0.74 dB
121	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Ring Wave Generator a. Voltage Amplitude (Voltage Decay) Pk2 40% to 110% of Pk1, Pk3 40 to 80% of Pk2, Pk4 40% to 80% of Pk3	Using Digital Storage Oscilloscope , High voltage Differential probe as per IEC 61000-4-12 by Direct Method	±0.25 kV to ±7.0 kV	4 %
122	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Ring Wave Generator - current amplitude	Using Digital Storage Oscilloscope , Current probe as per IEC 61000-4-12 by Direct Method	±8.33 A to ±583.33 A	1.96 %
123	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Ring Wave Generator - Voltage Rise time	Using Digital Storage Oscilloscope , High voltage Differential probe as per IEC 61000-4-12 by Direct Method	0.5 µs	0.008 µs
124	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Ring Wave Generator -Current rise time	Using Digital Storage Oscilloscope , Current probe as per IEC 61000-4-12 by Direct Method	1 µs	0.008 µs



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125	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Ring Wave Generator c)Oscillation frequency(period)	Using Digital Storage Oscilloscope , High voltage Differential probe as per IEC 61000-4-12 by Direct Method	100 kHz (10µs)	1.20 %
126	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Telecom surge Generator - Current Amplitude	Using Current Probe & Digital Oscilloscope as per IEC 61000-4-5 by Direct Method	±6.25 A to ±466.66 A	1.90 %
127	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Telecom surge test system - current front time	Using Digital Storage Oscilloscope, Current probe as per IEC 61000-4-5 by Direct Method	5 µs	0.02 µs
128	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Telecom surge test system - current pulse width	Using Digital Storage Oscilloscope, Current probe as per IEC 61000-4-5 by Direct Method	320 µs	0.2 µs
129	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Telecom surge test system - Voltage Amplitude	Using Digital Storage Oscilloscope , High voltage Differential probe as per IEC 61000-4-5 by Direct Method	±0.25 kV to ±7.0 kV	5.68 %



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130	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Telecom surge test system - Voltage front time	Using Digital Storage Oscilloscope , High voltage Differential probe as per IEC 61000-4-5 by Direct Method	10 μ s	0.015 μ s
131	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Telecom surge test system Voltage pulse width	Using Digital Storage Oscilloscope , High voltage Differential probe as per IEC 61000-4-5 by Direct Method	700 μ s	0.42 μ s
132	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Voltage Dips & Interruption Generator Dips/Interruption time	Using Digital Storage Oscilloscope, High voltage Differential probe as per IEC 61000-4-11 & IEC 61000-4-29 by Direct Method	10 ms to 5 s	0.83 %
133	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Voltage Dips & Interruption Generator Output voltage at no load	Using Digital Storage Oscilloscope, High voltage Differential probe as per IEC 61000-4-11 & IEC 61000-4-29 by Direct Method	0 % to 100 %	1.33 %



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134	ELECTRO-TECHNICAL-EMI/ EMC (Measure)	Voltage Dips & Interruption Generator Rise/Fall Time(with Load)	Using Voltage Differential Probe & Digital Oscilloscope as per IEC 61000-4-11 & IEC 61000-4-29 by Direct Method	1 μ s to 50 μ s	6.5 %
135	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	AM Modulation (CF :2 MHz to 3.5 GHz) (Mod Rate :50 Hz to 100 kHz)	Using Signal Analyser by Direct Method	5 % to 99 %	0.24 % to 1.1 %
136	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	Displayed Average Noise Level @ 1 MHz to 44 GHz	Using Signal Analyser & Signal Generator by Direct /Comparison Method	-90 dBm to -160 dBm	2.5 dB
137	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	FM Modulation (CF :2 MHz to 3.5 GHz) (Mod Rate :20 Hz to 50 kHz)	Using Signal Analyser by Direct Method	200 kHz to 400 kHz	3.1 kHz to 6.3 kHz
138	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	Frequency	Using Signal Analyser by Direct Method	9 kHz to 40 GHz	0.0012 % to 0.000022 %



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139	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	Microwave Power @ 10 MHz to 18 GHz	Using Power sensor by Direct Method	-60 dBm to 20 dBm	0.52 dB
140	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	Microwave Power @ 100 kHz to 22 GHz	Using Signal Analyser by Direct Method	-60 dBm to 13 dBm	0.5 dB
141	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	Microwave Power @ 26.5 GHz to 40 GHz	Using Signal Analyser by Direct Method	-135 dBm to 21 dBm	1.35 dB to 1.14 dB
142	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	Microwave Power @ 300 kHz to 26.5 GHz	Using Signal Analyser by Direct Method	-135 dBm to 21 dBm	1.16 dB to 1.36 dB
143	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	Phase Noise @ 0.1 kHz to 1MHz	Using Signal Analyser by Direct Method	-80 dBc/Hz to -150 dBc/Hz	1.43 dB to 2.52 dB



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144	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Measure)	PM Modulation (CF :2 MHz to 3.5 GHz) (Mod Rate :50 Hz to 50 kHz)	Using Signal Analyser by Direct Method	0.3 rad to 10 rad	0.009 rad to 0.43 rad
145	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	AM Modulation (CF :1 MHz to 5 GHz) (Mod Rate :50 Hz to 100 kHz)	Using Signal Generator by Direct Method	5 % to 99 %	1.2 % to 1.95 %
146	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	FM Modulation (CF :1 MHz to 3.5 GHz) (Mod Rate :20 Hz to 50 kHz)	Using Signal Generator by Direct Method	200 kHz to 400 kHz	2.8 kHz to 5.5 kHz
147	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	Frequency	Using Signal Generator by Direct Method	9 kHz to 40 GHz	0.000021 % to 0.000019 %
148	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	Harmonic Spurious 2nd Harmonic Fund. Freq. :1 MHz to 20 GHz	Using Signal Generator by Direct Method	-25 dBc to -100 dBc	1.43 dB to 2.34 dB



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149	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	Harmonic Spurious3rd Harmonic Fund. Freq. :1 MHz to 10 GHz	Using Signal Generator by Direct Method	-25 dBc to -100 dBc	2.3 dB to 3.75 dB
150	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	Microwave Power @3 GHz to 20 GHz	Using Signal Generator by Direct Method	-135 dBm to -90 dBm	0.56 dB
151	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	Microwave Power @3 GHz to 40 GHz	Using Signal Generator by Direct Method	-90 dBm to 15 dBm	0.56 dB to 0.45 dB
152	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	Microwave Power @9 kHz to 3 GHz	Using Signal Generator by Direct Method	-135 dBm to 20 dBm	0.42 dB to 0.56 dB
153	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	PM Modulation (CF :1 MHz to 3.5 GHz) (Mod Rate :50 Hz to 50 kHz)	Using Signal Generator by Direct Method	0.3 rad to 10 rad	0.015 rad to 0.14 rad



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154	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	SSB Phase Noise @ 250 MHz to 20 GHz	Using Signal Generator by Direct Method	-90 dBc/Hz to -140 dBc/Hz	2.5 dB
155	ELECTRO-TECHNICAL-RF/MICROWAVE (1 GHZ AND ABOVE) (Source)	Sub-Harmonic Spurious Multiple of fund. Freq by 0.5Fund. Freq. :1.6 GHz to 40 GHz	Using Signal Generator by Direct Method	-50 dBc to -130 dBc	3.8 dB to 1.8 dB
156	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	RTD	Using 61/2 DMM by Direct Method	-200 ° C to 800 ° C	0.12 ° C
157	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "B Type"	Using MPC by Direct Method	1000 ° C to 1820 ° C	0.4 ° C
158	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "B Type"	Using MPC by Direct Method	600 ° C to 1000 ° C	0.48 ° C



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159	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "C Type"	Using MPC by Direct Method	1500 ° C to 2315 ° C	0.71 ° C
160	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "C Type"	Using MPC by Direct Method	200 ° C to 1500 ° C	0.41 ° C
161	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "E Type"	Using MPC by Direct Method	-200 ° C to 1000 ° C	0.28 ° C
162	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "J Type"	Using MPC by Direct Method	-200 ° C to 500 ° C	0.08 ° C
163	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "J Type"	Using MPC by Direct Method	500 ° C to 1200 ° C	0.08 ° C
164	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "K Type"	Using MPC by Direct Method	-200 ° C to 1370 ° C	0.1 ° C



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165	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "L Type"	Using MPC by Direct Method	-200 ° C to 900 ° C	0.19 ° C
166	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "N Type"	Using MPC by Direct Method	-200 ° C to 1300 ° C	0.069 ° C
167	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "R Type"	Using MPC by Direct Method	20 ° C to 1760 ° C	0.19 ° C
168	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "S Type"	Using MPC by Direct Method	20 ° C to 1760 ° C	0.13 ° C
169	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "T Type"	Using MPC by Direct Method	-200 ° C to 400 ° C	0.064 ° C
170	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Measure)	Thermocouple "U Type"	Using MPC by Direct Method	-200 ° C to 600 ° C	0.204 ° C



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171	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	RTD	Using MPC by Direct Method	100 ° C to 800 ° C	0.21 ° C
172	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	RTD	Using MPC by Direct Method	-200 ° C to 100 ° C	0.08 ° C
173	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "B Type"	Using MPC by Direct Method	1000 ° C to 1820 ° C	0.31 ° C
174	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "B Type"	Using MPC by Direct Method	600 ° C to 1000 ° C	0.4 ° C
175	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "C Type"	Using MPC by Direct Method	1500 ° C to 2315 ° C	0.71 ° C
176	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "C Type"	Using MPC by Direct Method	200 ° C to 1500 ° C	0.41 ° C



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177	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "E Type"	Using MPC by Direct Method	-200 ° C to 1000 ° C	0.092 ° C
178	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "J Type"	Using MPC by Direct Method	-200 ° C to 500 ° C	0.08 ° C
179	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "J Type"	Using MPC by Direct Method	500 ° C to 1200 ° C	0.067 ° C
180	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "K Type"	Using MPC by Direct Method	-200 ° C to 1370 ° C	0.1 ° C
181	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "L Type"	Using MPC by Direct Method	-200 ° C to 900 ° C	0.19 ° C
182	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "N Type"	Using MPC by Direct Method	-200 ° C to 1300 ° C	0.056 ° C



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183	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "R Type"	Using MPC by Direct Method	20 ° C to 1760 ° C	0.092 ° C
184	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "S Type"	Using MPC by Direct Method	20 ° C to 1760 ° C	0.061 ° C
185	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "T Type"	Using MPC by Direct Method	-200 ° C to 400 ° C	0.056 ° C
186	ELECTRO-TECHNICAL-TEMPERATURE SIMULATION (Source)	Thermocouple "U Type"	Using MPC by Direct Method	-200 ° C to 600 ° C	0.2 ° C
187	ELECTRO-TECHNICAL-TIME & FREQUENCY (Measure)	Frequency	Using 6½ DMM by Direct Method	100 Hz to 300 kHz	0.041 % to 0.023 %
188	ELECTRO-TECHNICAL-TIME & FREQUENCY (Measure)	Frequency	Using 6½ DMM by Direct Method	3 Hz to 100 Hz	0.23 % to 0.041 %



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189	ELECTRO-TECHNICAL-TIME & FREQUENCY (Measure)	Time	Using Digital Timer by Comparison Method	0.1 s to 60 s	0.01 s to 0.02 s
190	ELECTRO-TECHNICAL-TIME & FREQUENCY (Measure)	Time	Using Digital Timer by Comparison Method	1 hr to 24 hr	0.12 s to 3.3 s
191	ELECTRO-TECHNICAL-TIME & FREQUENCY (Measure)	Time	Using Digital Timer by Comparison Method	60 s to 1 hr	0.02 s to 0.12 s
192	ELECTRO-TECHNICAL-TIME & FREQUENCY (Source)	Frequency	Using MPC by Direct Method	0.1 Hz to 100 kHz	5.81 % to 0.006 %
193	ELECTRO-TECHNICAL-TIME & FREQUENCY (Source)	Frequency	Using MPC by Direct Method	100 kHz to 2 MHz	0.006 % to 0.029 %
194	MECHANICAL-ACCELERATION AND SPEED	Centrifuge	Using Digital Tachometer by Direct Method	1000 rpm to 10000 rpm	1.5 rpm



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195	MECHANICAL-ACCELERATION AND SPEED	Centrifuge	Using Digital Tachometer by Direct Method	10000 rpm to 35000 rpm	2.3 rpm
196	MECHANICAL-ACCELERATION AND SPEED	Centrifuge/Stirrer	Using Digital Tachometer by Direct Method	100 rpm to 1000 rpm	1.2 rpm
197	MECHANICAL-ACCELERATION AND SPEED	RPM Calibrator/Tachometer Calibrator/RPM Source	Using Digital Tachometer by Direct Method	10 rpm to 1000 rpm	0.48 rpm
198	MECHANICAL-ACCELERATION AND SPEED	RPM Calibrator/Tachometer Calibrator/RPM Source	Using Digital Tachometer by Direct Method	1000 rpm to 10000 rpm	1.3 rpm
199	MECHANICAL-ACCELERATION AND SPEED	RPM Calibrator/Tachometer Calibrator/RPM Source	Using Digital Tachometer by Direct Method	10000 rpm to 50000 rpm	3.2 rpm
200	MECHANICAL-ACCELERATION AND SPEED	RPM Calibrator/Tachometer Calibrator/RPM Source	Using Digital Tachometer by Direct Method	50000 rpm to 90000 rpm	3.2 rpm
201	MECHANICAL-ACCELERATION AND SPEED	Tachometer (Contact)	Using Digital Tachometer and Tachometer Calibrator by Comparison Method	10 rpm to 1000 rpm	0.46 rpm



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202	MECHANICAL-ACCELERATION AND SPEED	Tachometer (Contact)	Using Digital Tachometer and Tachometer Calibrator by Comparison Method	1000 rpm to 6000 rpm	0.86 rpm
203	MECHANICAL-ACCELERATION AND SPEED	Tachometer (Non Contact)	Using Digital Tachometer and Tachometer Calibrator by Comparison Method	10 rpm to 1000 rpm	0.60 rpm
204	MECHANICAL-ACCELERATION AND SPEED	Tachometer (Non Contact)	Using Digital Tachometer and Tachometer Calibrator by Comparison Method	1000 rpm to 10000 rpm	1.2 rpm
205	MECHANICAL-ACCELERATION AND SPEED	Tachometer (Non Contact)	Using Digital Tachometer and Tachometer Calibrator by Comparison Method	10000 rpm to 50000 rpm	3.2 rpm
206	MECHANICAL-ACCELERATION AND SPEED	Tachometer (Non Contact)	Using Digital Tachometer and Tachometer Calibrator by Comparison Method	50000 rpm to 90000 rpm	3.6 rpm



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207	MECHANICAL-PRESSURE INDICATING DEVICES	Absolute Pressure(Pneumatic) : Absolute pressure gauges / Barometers / Manometers / Absolute pressure calibrators, Pressure Switches, Pressure Transducers / Transmitters	Using Absolute Pressure calibrator with Digital Multimeter & Pneumatic Hand Pump by Comparison Method as per DKD-R 6-1	0.2 bar(a) to 7 bar(a)	0.0015 bar(a)
208	MECHANICAL-PRESSURE INDICATING DEVICES	Low Pressure (Pneumatic): Magnehelic gauges / Low Pressure gauges/Low pressure Transmitters and Switches	Using Digital Pressure Gauge, Digital Multimeter & Pneumatic Hand Pump by Comparison Method DKD R-6-1	0 to 200 mbar	0.064 mbar
209	MECHANICAL-PRESSURE INDICATING DEVICES	Negative Pressure: Magnehelic gauges/ Low Pressure gauges/Low pressure Transmitters and switches	Using Digital Pressure Gauge, Digital Multimeter & Pneumatic Hand Pump by Comparison Method DKD R-6-1	(-)200 mbar to 0 mbar	0.064 mbar



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210	MECHANICAL-PRESSURE INDICATING DEVICES	Negative pressure: Vacuum Gauges, Vacuum Calibrators, Pressure Switches, Pressure Transmitters	Using Digital Pressure Gauge, Digital Multimeter & Pneumatic Hand Pump by Comparison Method DKD R-6-1	(-)0.95 bar to 0 bar	0.0003 bar
211	MECHANICAL-PRESSURE INDICATING DEVICES	Pressure (Hydraulic): Pressure gauges, Pressure Calibrators, Pressure Switches , Pressure Transmitters	Using Digital Pressure Gauge, Digital Multimeter & Hydraulic Comparator by Comparison Method DKD R-6-1	0 to 200 bar	0.038 bar
212	MECHANICAL-PRESSURE INDICATING DEVICES	Pressure (Hydraulic): Pressure gauges, Pressure Calibrators, Pressure Switches , Pressure Transmitters	Using Digital Pressure Gauge, Digital Multimeter & Hydraulic Comparator by Comparison Method DKD R-6-1	0 to 350 bar	0.1 bar
213	MECHANICAL-PRESSURE INDICATING DEVICES	Pressure (Hydraulic): Pressure gauges, Pressure Calibrators, Pressure Switches , Pressure Transmitters	Using Digital Pressure Gauge, Digital Multimeter & Hydraulic Comparator by Comparison Method DKD R-6-1	0 to 70 bar	0.011 bar



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214	MECHANICAL-PRESSURE INDICATING DEVICES	Pressure (Hydraulic): Pressure gauges, Pressure Calibrators, Pressure Switches , Pressure Transmitters	Using Digital Pressure Gauge, Digital Multimeter & Hydraulic Comparator by Comparison Method DKD R-6-1	0 to 700 bar	0.11 bar
215	MECHANICAL-PRESSURE INDICATING DEVICES	Pressure(Pneumatic) : Pressure gauges, Pressure Calibrators, Pressure Switches, Pressure Transmitters	Using Digital Pressure Gauge, Digital Multimeter & Pneumatic Hand Pump by Comparison Method DKD R-6-1	0 to 10 bar	0.0026 bar
216	MECHANICAL-PRESSURE INDICATING DEVICES	Pressure(Pneumatic) : Pressure gauges, Pressure Calibrators, Pressure Switches, Pressure Transmitters	Using Digital Pressure Gauge, Digital Multimeter & Pneumatic Hand Pump by Comparison Method DKD R-6-1	0 to 2 bar	0.0005 bar
217	MECHANICAL-PRESSURE INDICATING DEVICES	Pressure(Pneumatic) : Pressure gauges, Pressure Calibrators, Pressure Switches, Pressure Transmitters	Using Digital Pressure Gauge, Digital Multimeter & Pneumatic Hand Pump by Comparison Method DKD R-6-1	0 to 40 bar	0.0096 bar



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218	THERMAL-SPECIFIC HEAT & HUMIDITY	Humidity Chamber (Multipositions) @ (10 °C to 95 °C)	Using RTD's and Multichannel Recorder by Wet & Dry Bulb Method	10 %rh to 95 %rh	3.5 %rh
219	THERMAL-SPECIFIC HEAT & HUMIDITY	Humidity Chamber (Multipositions) @ (25 °C to 50 °C)	Using Temperature & Humidity Data Loggers (minimum 3 Nos) by Comparison Method	10 % rh to 95 % rh	2.0 % rh
220	THERMAL-SPECIFIC HEAT & HUMIDITY	Humidity Chamber (Multipositions) @ (10 %rh to 95 %rh)	Using RTD's and Multichannel Recorder by Wet & Dry Bulb Method	10 °C to 95 °C	0.52 °C
221	THERMAL-SPECIFIC HEAT & HUMIDITY	Humidity Chamber (Multipositions) @ (50% RH)	Using Temperature & Humidity Data Loggers(minimum 3 Nos) by Comparison Method	10 °C to 60 °C	0.5 °C
222	THERMAL-SPECIFIC HEAT & HUMIDITY	Thermo Hygrometer, Humidity Transmitter, Humidity Indicator with Sensor @ (10 °C to 60 °C)	Using Humidity Chamber with Digital Temperature & Humidity Indicator with Sensor by Comparison Method	10 %rh to 95 %rh	1.6 %rh



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223	THERMAL-SPECIFIC HEAT & HUMIDITY	Thermo Hygrometer, Humidity Transmitter, Humidity Indicator with Sensor @ (50 % rh)	Using Humidity Chamber with Digital Temperature & Humidity Indicator with Sensor and PRT with Indicator by Comparison Method	6 °C to 60 °C	0.29 °C
224	THERMAL-TEMPERATURE	Black Body Source, IR Calibrator	Using Non Contact IR Thermometer (Emissivity: 0.95) by Comparison Method	(-)30 °C to 100 °C	1.2 °C
225	THERMAL-TEMPERATURE	Black Body Source, IR Calibrator	Using Non Contact IR Thermometer (Emissivity: 0.95) by Comparison Method	100 °C to 500 °C	1.8 °C
226	THERMAL-TEMPERATURE	Deep Freezers, Refrigerators, Chambers (Multi-Position)	Using Standard RTD's with Data Logger By Comparison Method	(-)80 °C to 25 °C	0.78 °C
227	THERMAL-TEMPERATURE	Incubators, Autoclaves(Non-Medical purpose), Chambers, Oven (Multi-Position)	Using Standard RTD's with Data Logger (minimum three No's)By Comparison Method	25 °C to 300 °C	0.75 °C



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S.No	Discipline / Group	Measurand or Reference Material/Type of instrument or material to be calibrated or measured / Quantity Measured /Instrument	Calibration or Measurement Method or procedure	Measurement range and additional parameters where applicable(Range and Frequency)	* Calibration and Measurement Capability(CMC)(±)
228	THERMAL-TEMPERATURE	Indicator with Sensor of Temperature Bath, Temperature Calibrator, Oven, Furnace (Single Position)	Using Standard PRT with Indicator By Comparison Method	200 °C to 500 °C	0.14 °C
229	THERMAL-TEMPERATURE	Indicator with Sensor of Deep Freezers, Refrigerators, Temperature Bath, Temperature Calibrator, Temperature Chambers (Single Position)	Using Standard PRT with Indicator By Comparison Method	(-)80 °C to 25 °C	0.152 °C
230	THERMAL-TEMPERATURE	Indicator with Sensor of Incubators, Autoclaves(Non-Medical purpose), Temperature Bath, Temperature Calibrator, Temperature Chambers, Oven (Single Position)	Using Standard PRT with Indicator By Comparison Method	25 °C to 200 °C	0.13 °C



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231	THERMAL-TEMPERATURE	Indicator with Sensor of Temperature Bath, Temperature Calibrator, Furnace (Single Position)	Using Standard 'S' type thermocouple with Indicator By Comparison Method	500 °C to 1200 °C	2.0 °C
232	THERMAL-TEMPERATURE	Infrared, Non-Contact Thermometer, Pyrometer, Thermal Imager (Temp. only)	Using Non-Contact IR Thermometer (Emissivity: 0.95) and Black Body Source By Comparison Method	(-)20 °C to 50 °C	1.57 °C
233	THERMAL-TEMPERATURE	Infrared, Non-Contact Thermometer, Pyrometer, Thermal Imager (Temp. only)	Using Non-Contact IR Thermometer (Emissivity: 0.95) and Black Body Source By Comparison Method	50 °C to 500 °C	2.11 °C
234	THERMAL-TEMPERATURE	Oven, Furnace (Multi-Position)	Using Standard 'N' Type Thermocouples with Data Logger By Comparison Method	300 °C to 1000 °C	3.2 °C



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235	THERMAL-TEMPERATURE	RTD with /without indicator, Thermocouple with/without indicator, Temperature Gauges, Temperature Transmitter with/without indicator	Using Standard PRT with Indicator and Dry Temperature Bath and 6.5 digit DMM By Comparison Method	(-)30 °C to 100 °C	0.11 °C
236	THERMAL-TEMPERATURE	RTD with /without indicator, Thermocouple with/without indicator, Temperature Gauges, Temperature Transmitter with/without indicator	Using Standard PRT with Indicator and Dry Temperature Bath and 6.5 digit DMM By Comparison Method	100 °C to 650 °C	0.13 °C
237	THERMAL-TEMPERATURE	Thermocouple with/without indicator, Temperature Transmitter with/without indicator	Using Standard 'S' Type Thermocouple with Indicator and Dry Temperature Bath and DMM By Comparison Method	650 °C to 1200 °C	1.92 °C

* CMCs represent expanded uncertainties expressed at approximately the 95% level of confidence, using a coverage factor of $k = 2$.